

<b>Notice of References Cited</b>	Application/Control No. 09/919,171	Attendant(s)/Patent Under Reexam KOO et al.
	Examiner Daniel Larkin	Art Unit 2856

#### U.S. PATENT DOCUMENTS

	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
A	3,478,205	11/1969	Sporek	73	23.35
B	3,656,339	4/1972	Narain	73	23.35
C	5,955,886	9/1999	Cohen et al.	73	23.4
D	6,012,326	1/2000	Raybone et al.	73	31.03
E					
F					
G					
H					
I					
J					
K					
L					
M					

#### FOREIGN PATENT DOCUMENTS

	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Country	Name	Classification <sup>2</sup>	
N						
O						
P						
Q						
R						
S						
T						

#### NON-PATENT DOCUMENTS

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages	
U	Dai, P. et al., "A Novel High Sensitivity Micro GC Detector", Transducers '99, June 7-10, 1999, pp. 696-699.	
V	Koo, J.C. et al., "Glow Discharge Detector", 7 June 1999, pp. 1-15.	
W		
X		

\* A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).

<sup>1</sup> Dates in MM-YYYY format are publication dates.

<sup>2</sup> Classifications may be U.S. or foreign.